6. (Currently Amended) The method of ~~as claimed in~~ claim 5 wherein ~~, in which~~ the special measurement is a measurement for checking the quality of the at least one marked physical object ~~marked~~.

7. (Currently Amended) The method of claim 1, further comprising ~~as claimed in one of claims 1 to 6, in which~~

continuing the manufacturing process for any of the plurality of ~~the~~ physical objects not marked as failing the prescribed selection criterion ~~are further treated according to the manufacturing process~~.

8. (Currently Amended) The method of claim 1, wherein ~~as claimed in one of claims 1 to 7, in which~~ the selection criterion is a quality characteristic of the manufacturing process.

9. (Currently Amended) The method of claim 1, wherein ~~as claimed in one of claims 1 to 8, in which~~ the selection criterion is ~~considered as~~ not satisfied if a value of the at least one process parameter goes above or below a prescribed limit value.

10. (Currently Amended) A device for ~~the~~ monitoring ~~of~~ a manufacturing process of a plurality of physical objects with a processor which is set up in such a way that the following method steps can be carried out:

performing an analysis ~~by~~ using values of at least one process parameter of the manufacturing process of the plurality of physical objects ~~object~~;

marking at least one ~~of~~ physical object ~~objects~~ when, as a result of the analysis, the at least one physical object does not satisfy a prescribed selection criterion; ~~is not satisfied; and~~

removing the at least one marked physical object from the manufacturing process; and

sending the at least one marked physical object ~~associated physical objects~~ for special treatments.

11. (Currently Amended) A computer-readable storage medium, in which a program for ~~the~~ monitoring ~~of~~ a manufacturing process of a plurality of physical objects is stored, ~~which~~ the program performing ~~performs~~ the following method steps when it is run by a processor:

performing analysis ~~by~~ using values of at least one process parameter of the manufacturing process of the plurality of physical objects ~~object~~;

marking at least one ~~of~~ physical object ~~objects~~ when, as a result of the analysis, the at least one physical object does not satisfy a prescribed selection criterion; ~~is not satisfied; and~~

removing the at least one marked physical object from the manufacturing process; and

sending the at least one marked physical object ~~associated physical objects~~ for special treatments.

12. (Currently Amended) A computer program element for ~~the~~ monitoring ~~of~~ a manufacturing process of a plurality of physical objects, the computer program executing ~~which has~~ the following method steps when it is run by a processor:

performing an analysis ~~by~~ using values of at least one process parameter of the manufacturing process of the plurality of physical objects ~~object~~;

marking at least one ~~of~~ physical object ~~objects~~ when, as a result of the analysis, the at least one physical object does not satisfy a prescribed selection criterion; ~~is not satisfied; and~~

removing the at least one marked physical object from the manufacturing process; and

sending the at least one marked physical object ~~associated physical objects~~ for special treatments.

13. (New) The method of claim 1, further comprising:

preventing values associated with the at least one marked physical object from affecting an average product quality of the plurality of physical objects.

14. (New) The device of claim 10, wherein the processor is further set up to carry out the step of:

preventing values associated with the at least one marked physical object from affecting an average product quality of the plurality of physical objects.

15. (New) The computer-readable storage medium of claim 11, wherein the program further performs the step of:

preventing values associated with the at least one marked physical object from affecting an average product quality of the plurality of physical objects.

16. (New) The computer program element of claim 12, wherein the computer program further executes the step of:

preventing values associated with the at least one marked physical object from affecting an average product quality of the plurality of physical objects.

I. Introduction

Claims 1-12 are pending in the application. In the Office Action dated Feb. 9, 2005, the Examiner rejected claims 1-12 under 35 U.S.C. § 102(e) as being anticipated by U.S. Pat. No. 6,647,309 ("Bone"). In this Amendment, claims 1-12 have been amended and claims 13-16 have been added. Applicant respectfully requests reconsideration of the claims and withdrawal of the rejection in light of the amendments to the claims and the following remarks.

II. Bone Does Not Anticipate the Currently-Claimed Invention

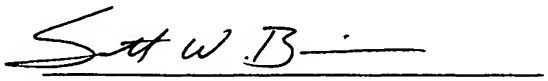
Amended independent claims 1, 10, 11, and 12 are all directed to a system for monitoring the manufacture of a plurality of objects. Generally, claims 1, 10, 11, and 12 disclose a system that performs an analysis of a manufacturing process using at least one process parameter value. The result of the analysis is used to mark any of the plurality of physical objects that do not satisfy prescribed criteria. Any physical object marked as not meeting the prescribed criteria is sent for special treatments and ***removed from the manufacturing process***. Bone fails to disclose at least the limitation of removing physical objects that do not satisfy prescribed criteria from the manufacturing process.

Bone is directed to a method and apparatus for automated generation of test semiconductor wafers. Bone discloses manufacturing test wafers and then measuring the test wafers to determine whether any out-of-control events occurred during the manufacture of the test wafers or whether any Statistical Process Control ("SPC") violations occurred during the manufacture of the test wafers. If an out-of-control event or any SPC violations occurred, more tests are performed on the test wafers to determine the cause of the out-of-control event or SPC violation. Due to the fact the special test wafers of Bone are not part of the normal plurality of production wafers, the test wafers never complete the manufacturing process. Therefore, Bone necessarily does not disclose a system that removes a physical object from a plurality of physical objects that is marked as not satisfying a prescribed criterion as in the currently-claimed invention. Applicants respectfully request reconsideration and withdrawal of the rejection to the pending claims under 35 U.S.C. § 102(e).

III. Conclusion

In view of the foregoing amendments, Applicants submit that the pending claims are in condition for allowance. Reconsideration is therefore respectfully requested. If there are any questions concerning this Response, the Examiner is asked to phone the undersigned attorney at (312) 321-4200.

Respectfully submitted,



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